

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1888	((438/5,7) or (700/121) or (356/508,509)).CCLS.	USPAT	OR	OFF	2006/06/28 11:36
L2	397	1 and (wafer same error)	USPAT	OR	ON	2006/06/28 11:36
L3	0	1 and (wafer same (mean adj error))	USPAT	OR	ON	2006/06/28 11:36
L4	2	1 and (mean adj error)	USPAT	OR	ON	2006/06/28 11:41
L5	267	1 and (wafer with error)	USPAT	OR	ON	2006/06/28 11:42
L6	25	5 and (field with error)	USPAT	OR	ON	2006/06/28 11:42

Search NIST Webspace

[A-Z subject index](#) [Search NIST webspace](#) [Contact NIST](#) [Home](#)

Advanced Search [Search Tips](#)

Searched for **wafer mean error**.

Results 1 - 10 of about 293. Search took 0.33 seconds.

[Next>](#)Sort by: [Date](#) / [Relevance](#)**[PDF] Recent Developments in Electrical Metrology for MOS Fabrication**

... CVC Model Parameters EOT = 7.35 Å Nsurf = 9.7E17 /cc Vfb = -0.252 V RMS fit **error** =
 +/-0.8% ... 8 Angstrom SiON Wafer Mean = 9.83 Ang. Sigma = 0.051 Ang. ...

www.eeel.nist.gov/812/conference/2005_Talks/Brown-Benjamin.pdf - 2005-03-21 - [Text Version](#)

3.3.3.3. Selecting Sample Sizes

... relative **error**, we wish to use absolute **error**, the equation ... a 500 Angstrom film on a semiconductor **wafer** in order to determine the process **mean** so that ...

www.itl.nist.gov/div898/handbook/ppc/section3/ppc333.htm - 11k - [Cached](#)

[PDF] Lumped-Element Models for On-Wafer Calibration

... Accurate on-wafer SOLR and OSLT calibrations at very ... the model is to systematic or random measurement **error**. ... and we note that the root-mean-square estimation ...

www.boulder.nist.gov/div818/81801/dylan/papers/models.pdf - 2001-03-20 - [Text Version](#)

[PDF] An Optimal Multiline TRL Calibration Algorithm

... two algorithms for one of our typical on-wafer calibrations. ... line in the figure shows the estimated **error** distribution generated from the **mean** of the ...

www.boulder.nist.gov/div818/81801/dylan/papers/MultilineNoise.pdf - 2003-09-23 - [Text Version](#)

[[More results from www.boulder.nist.gov/div818/81801/dylan](#)]

[PDF] Accuracy of AlGaAs growth rates and composition determination ...

... Although larger RHEED specimens better simulate the actual **wafer** in thermal environment and ... gP; and $\delta b \text{ Å} gP = \delta a \text{ gP}$: The **mean square error** in the ...

www.boulder.nist.gov/div815/81504_pubs/SCDocs/Harvey-JCG-03.pdf - 2003-05-08 - [Text Version](#)

[PDF] On-wafer measurements of noise temperature - Instrumentation and ...

... typically the standard deviation of the **mean** of several ... the measurements (except of the on- **wafer** diode) is ... Any **error** due to radiometer nonlinearity for these ...

www.boulder.nist.gov/div818/81801/Noise/publications/99_OWNT_IM.pdf - 2002-04-24 - [Text Version](#)

[PDF] A First Step towards a Wave-Based 'Stochastic' Calibration for ...

... One then has to rely on the **error** bounds that are ... lines are used as an on-wafer calibration ... is complex circular normal distributed with zero **mean**, that is ...

www.boulder.nist.gov/div818/81801/NonlinearDevCharPublicationsOnly/MetrologyPublications/ARFTG63_WaveC-2004-11-04.pdf - [Text Version](#)

[PDF] Microsoft PowerPoint - robdesgn.ppt

... a response - Deposition time in silicon **wafer** fabrication ... proportional to the **mean**.

Page 14. 8.14 ... σ 2 represents measurement **error** Page 16. 8.16 Replicates ...

www.itl.nist.gov/div898/education/dex/robdesgn/robdesgn.pdf - 2002-02-12 - [Text Version](#)

Search NIST Webspace

N
National Institute
of Standards and Technology

[A-Z subject index](#) [Search NIST webspace](#) [Contact NIST](#) [Home](#)

[Advanced Search](#) [Search Tips](#)

"wafer mean error"

Searched for "wafer mean error".

Search took 0.02 seconds.

Your search - "wafer mean error" - did not match any documents.

No pages were found containing ""wafer mean error"".

Suggestions:

- Make sure all words are spelled correctly.
- Try different keywords.
- Try more general keywords.

Powered by Google